

Notice of References Cited	Application/Control No. 10/602,744		Applicant(s)/Patent Under Reexamination BAEK ET AL.	
	Examiner Marissa L. Ferguson-Samreth		Art Unit 2854	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0118922	06-2003	Hayashi et al.	430/7
	B	US-			
	C	US-			
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	E	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

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